

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination THOM, FRANK	
	Examiner	Art Unit	Página 1 of 1
	Dah-Wei D. Yuan	1745	

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5,338,622	08-1994	Hsu et al.	429/26
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
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I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	WO 94/13026	06-1994	Europe	Hsu et al.	H01M 8/04
O	JP 9,007,624	01-1997	Japan	Kitamura et al.	H01M 8/04
P					
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S					
T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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